## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10813020	CHANG, YEN SHENG	
Examiner	Art Unit	
Bonura, Tim	2114	

SEARCHED						
Class	Subclass	Date	Examiner			
714	51, 55	1/6/2007	Tim Bonura			
713	500	1/6/2007	Tim Bonura			

SEARCH NOTES					
Search Notes	Date	Examiner			
Searched in East using: USPat, USPub, Derwent, EPO, JPO, IBM	1/6/2007	Tim Bonura			
Inventor Name Search	1/6/2007	Tim Bonura			
Consulted with Bryce Bonzo over class searching and NPL	1/6/2007	Tim Bonura			
NPL search	1/6/2007	Tim Bonura			

INTERFERENCE SEARCH						
Class	Subclass	Date	Examiner			
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